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pr	AA	3,412,456	11/68	Ebisawa			1	7		
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Ma	AC	4,105,970	8/78	Katz			5			
KIS	AD	4,141,055	2/79	Berry et al.						
Ke	AE	4,182,781	1/80	Hooper et al.)			
Re	AF	4,189,825	2/80	Robillard et al.			5		_	
Re	AG	4,312,117	1/82	Robillard et al.						
fee.	AH	4,315,984	2/82	Okazaki et al.	<u></u>	\			_	
NX.	AJ	4,417,206	11/83	Slowers			1	. (
Me	Ą	4,499,656	2/85	Fabian et al.	et al.			1		
RK	AK	4,585,991	4/86	Reid et al.	al.			 		
K	AL	4,881,118	11/89	Niwayama et al.		5	ζ	. ,		
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			OTHER REFEREN	ICES (including Author, Title, Da	te, Pertinent Pages, Etc.	.)				
W	AR	Moto's Nakano	*A Probe for Test	ting Semiconductor Integrated C	ircuits and a Test Met	thod Using S	Said Probe."	25 March, 1991		
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RI	- AU	4,92	4,589	5/90	Leedy		7	ζ	1	7		
RL	AV	4,92	9,999	5/90	Hoebrechts et al.		5					
RL	AW	4,93	7,653	6/90	Blonder et ai.							
RL	AX	4,95	2,272	8/90	Okino et al.							
Re	AY	4,96	3,225	10/90	Lehman-Lemar							
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Ple	ВА	5,014	4,161	5/91	Lee et al.							
Pl	ВВ	5,03	2,541	7/91	Sakamoto et al.	•				5		
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KK	BD	5,072,116		12/91	Kawade et al.	e et al.			5			
Re	BE	5,103,557		4/92	Leedy				5			
RI	BF	5,137,461		8/92	Bindra et al.	ndra et al.			<u> </u>			
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RK	во	5,177	·,438	1/93	Littlebur	y et al.		7	7	ζ		
16/	BP	5,177	,439	1/93	Liv et al			7	7	(
Re	BQ	5,196	.251	3/93	Bakhru e	et al.		7	5			
RK	BR	5,206	. 585	4/93	Chang ci	ı al.			. /	(
Rel	BS	5,235	,140	8/93	Reele et	al.	_	ζ				
Pul	вт	5,239	,260	8/93	Widder	et al.						
Ru	BU	5,245	,135	9/93	Schreiber	r et al.)	
Re	BV	5,262	L718	11/93	Svendsen	et al.		5				
Re	ВW	5,307	,561	5/94	Feigenba	igenbaum et al.						
R	вх	5,323	,035	6/97	Leedy			ζ		5		
RL	BY	5,326	i,428	7/94	Farnworth et al.				5			
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RU	а	5,353,	,195	10/94	Fillion et	al.		7)	-	5
Ru	CI	5,367,	,253	11/94	Wood et	al.		5	5	(
Re	CK	5,402.	,077	03/95	Agabdel	ct al.		(
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RL	СМ	5,431,	,328	07/95	Chang et	8].				/	/
Ph	CN	5,478,	.779	12/95	Akram	<u> </u>)		
Re	8	5,468,	,917	11/95	Brodsky (et al.					
KK	СР	5,471	,151	11/95	DiFrances	sco					
fle	CQ	5,477	,087	12/95	Kwakita (et al.			/		
Pla	CR	5,523	,697	06/96	Farnwort	h et al.)				
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PK	СТ	5,559	,444	09/93	Farnwortl	rnworth et al.			L)	
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RV	DC	5,62	15,297	04/97	Amaudov et al.				1))		
Ru	DD	5,71	6,218	02/98	Farnworth et al.	_				П			 		
R	DE	5,79	0,337	08/98	Schreiber et al.					П			1		
M	DF	5,83	1,832	11/98	Gillette et al.								7_		
RK	DG	5,849	9,633	12/98	Akram										
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RK	Dì	6,00	2,266	12/99	Briggs et al.								T_{\perp}		
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RK	DN	4,110	6,523	09/26/78	Coberly et al.	Coberly et al.							7		
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